

# 200 & 300 mm Compatible Contamination Monitoring Tool Lineup

## Total Reflection X-ray Fluorescence Spectrometer

### Detection Limit of typical elements (LLD)

Measurement time: 1,000 sec

LLD(example): atoms/cm<sup>2</sup>  
Sample: 300mm wafer

		Na	Al	Fe	Ni	Cu
200 mm & 300 mm Compatible	TXRF-V310	$2.0 \times 10^9$	$1.0 \times 10^9$	$1.0 \times 10^7$	$1.0 \times 10^7$	$1.0 \times 10^7$
	TXRF 310Fab	$2.5 \times 10^{11}$	$2.5 \times 10^{11}$	$1.0 \times 10^9$	$1.0 \times 10^9$	$1.5 \times 10^9$

\* Film type contamination

### Metal contamination monitor for $10^7$ atoms/cm<sup>2</sup> level VPD-integrated model of Total Reflection X-ray Fluorescence tool



# TXRFV310

- World's first VPD-integrated TXRF tool
- Na, Mg, Al~U analyzable
- High throughput
- High-sensitivity analysis
- 200 mm & 300 mm compatible
- No need for liquid nitrogen
- Available with VPD function for hydrophilic substrates